US00D920813S

(12) **United States Design Patent**
Zhan et al.

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(45) **Date of Patent:** ** **Jun. 1, 2021**

(54) **INSPECTION SYSTEM**

(71) Applicant: **Baker Hughes Oilfield Operations LLC**, Houston, TX (US)

(72) Inventors: **Yanmin Zhan**, Shanghai (CN); **Najie Jiao**, Shanghai (CN); **Sanmao Xiong**, Xi'an (CN); **Wenhan Fu**, Shanghai (CN); **Xiaoyu Jiang**, Shanghai (CN)

(73) Assignee: **BAKER HUGHES OILFIELD OPERATIONS LLC**, Houston, TX (US)

(**) Term: **15 Years**

(21) Appl. No.: **29/690,205**

(22) Filed: **May 6, 2019**

(51) **LOC (13) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/46**; D10/75; D10/81; D10/102; D24/186

(58) **Field of Classification Search**
USPC D10/46, 49, 75, 81, 102; D13/163; D14/302, 307, 388, 900, 902; D24/185, D24/186, 232, 233, 234
CPC G01N 21/95684; G01N 21/95607
See application file for complete search history.

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Primary Examiner — Antoine Duval Davis
(74) *Attorney, Agent, or Firm* — Mintz Levin Cohn Ferris Glovsky and Popeo, PC; Lisa Adams

(57) **CLAIM**

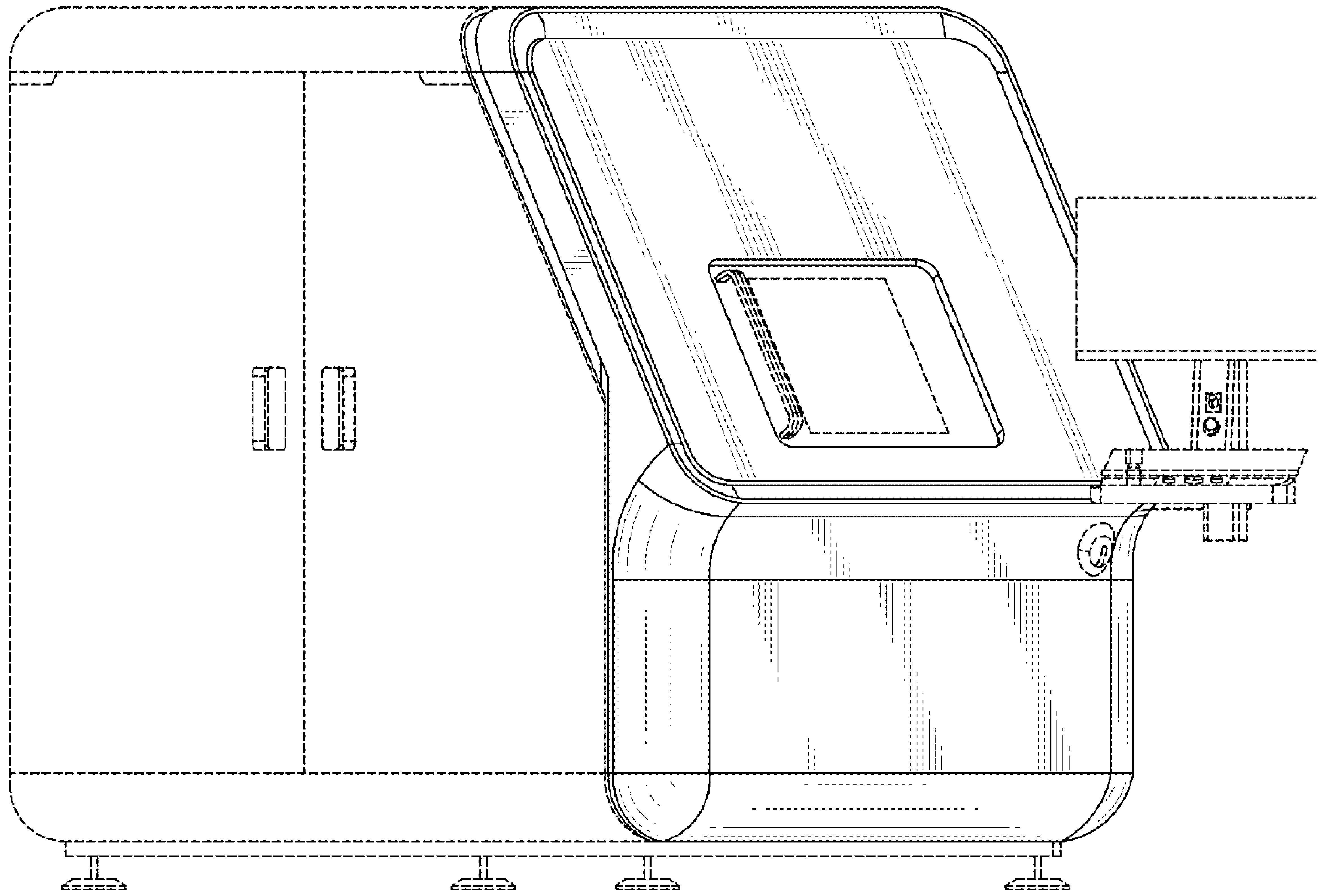
The ornamental design for an inspection system, as shown and described.

DESCRIPTION

FIG. **1** is a front view of an inspection system;
FIG. **2** is a side view thereof;
FIG. **3** is another side view thereof;
FIG. **4** is a top view thereof;
FIG. **5** is a bottom view thereof;
FIG. **6** is a front perspective view thereof;
FIG. **7** is a back perspective view thereof; and,
FIG. **8** is another front perspective view thereof.

The broken line illustration of portions of the inspection system in the drawing is for illustrative purposes and is not part of the claimed design.

1 Claim, 8 Drawing Sheets



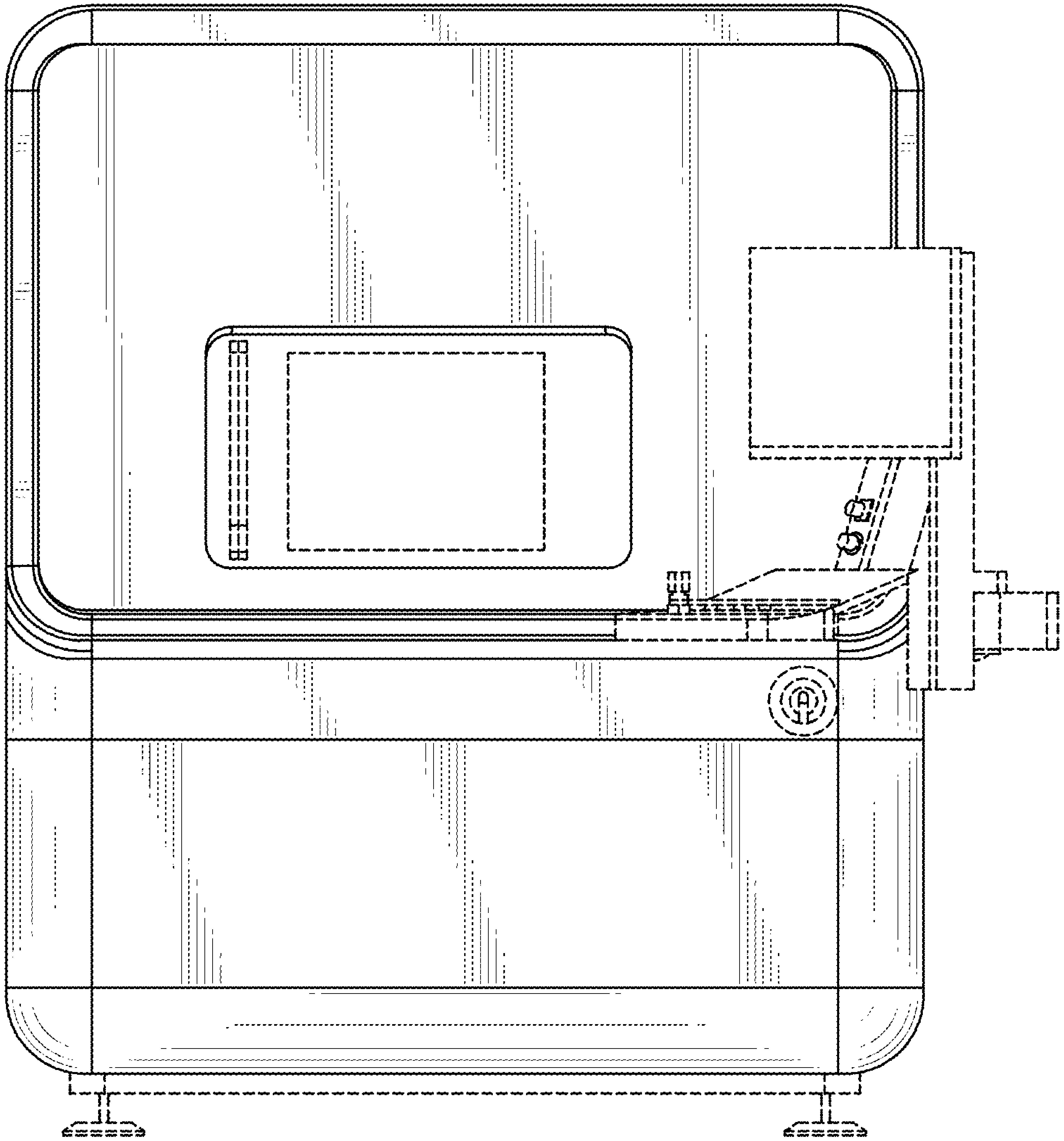


FIG. 1

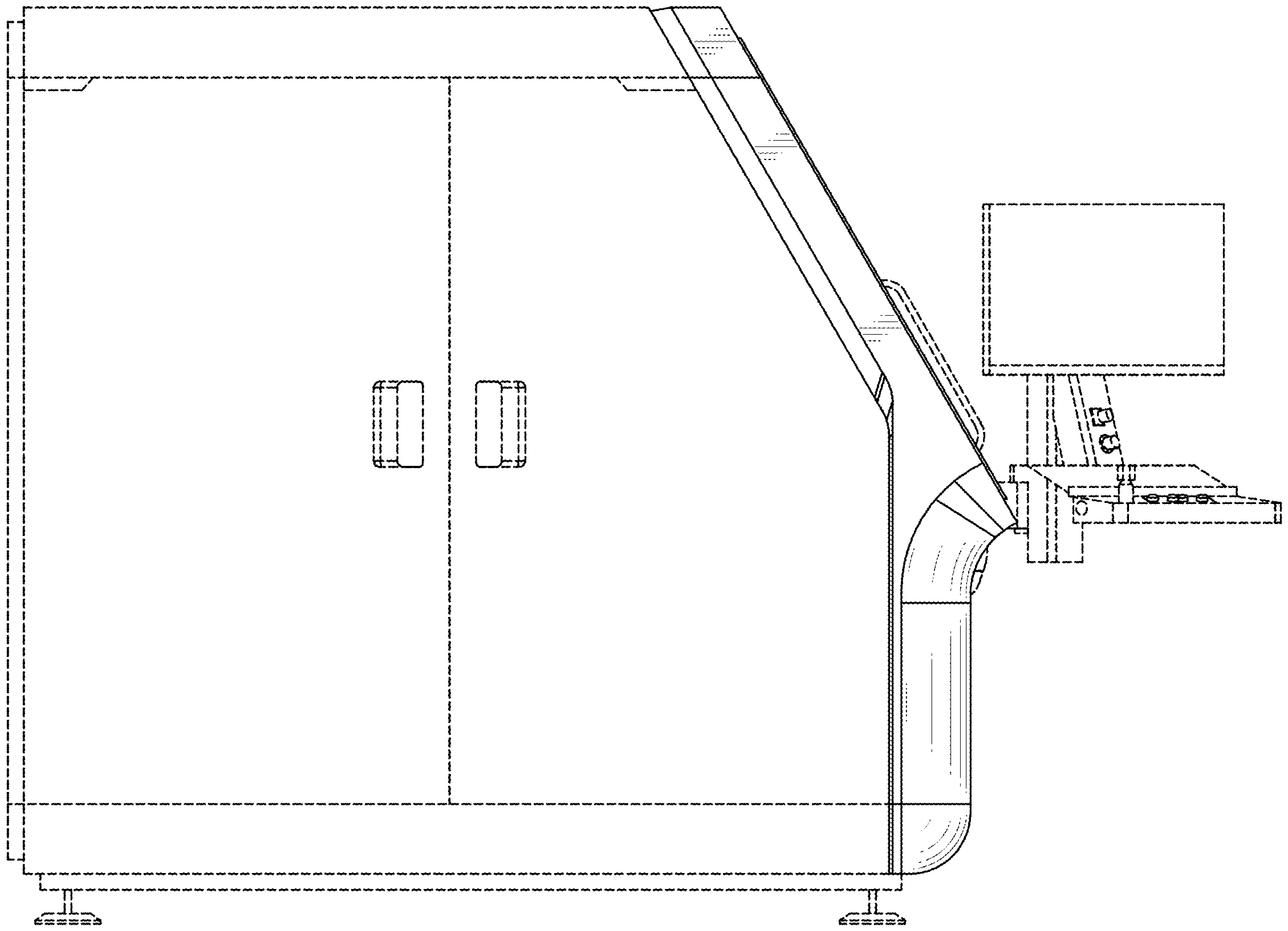


FIG. 2

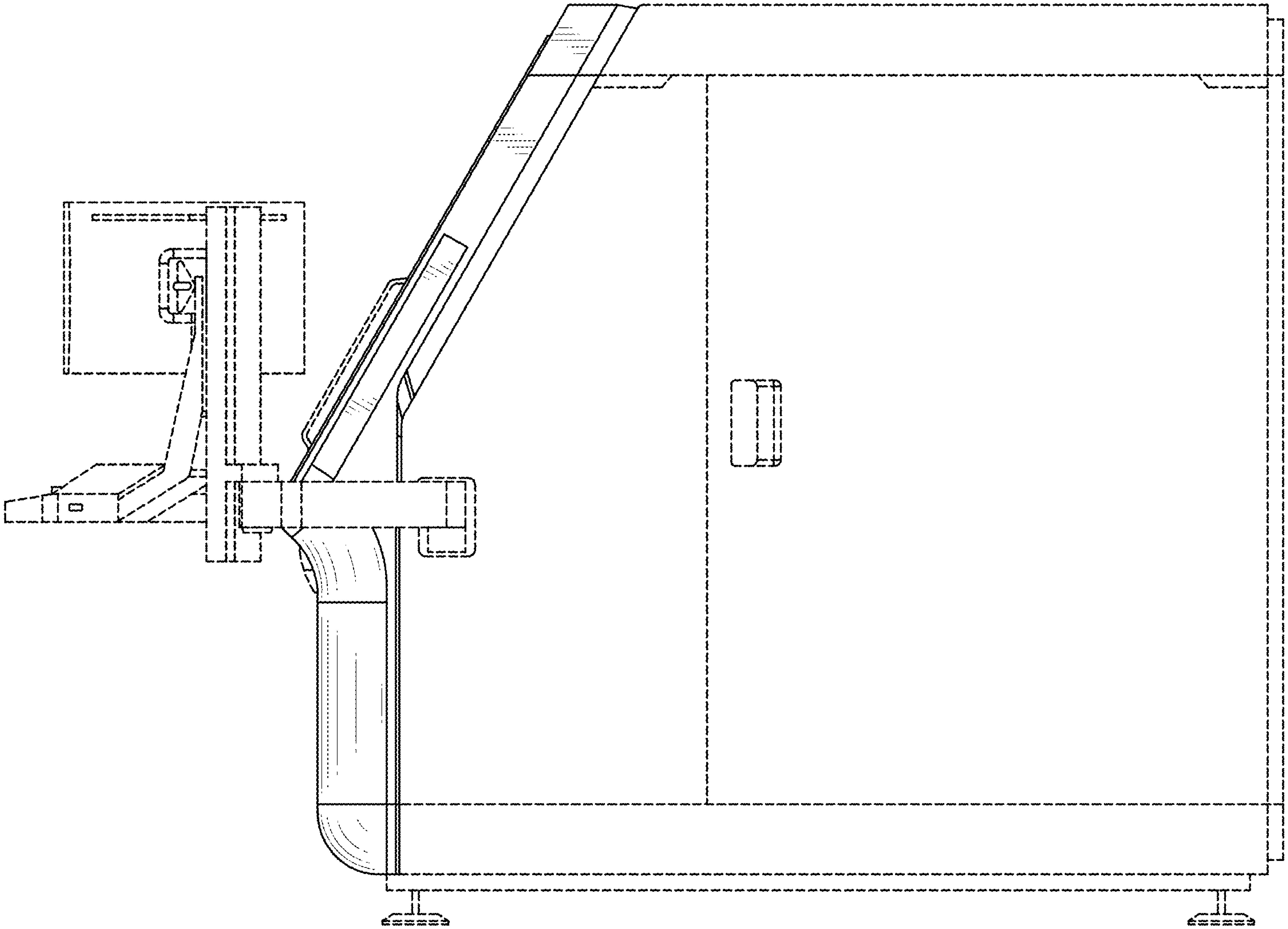


FIG. 3

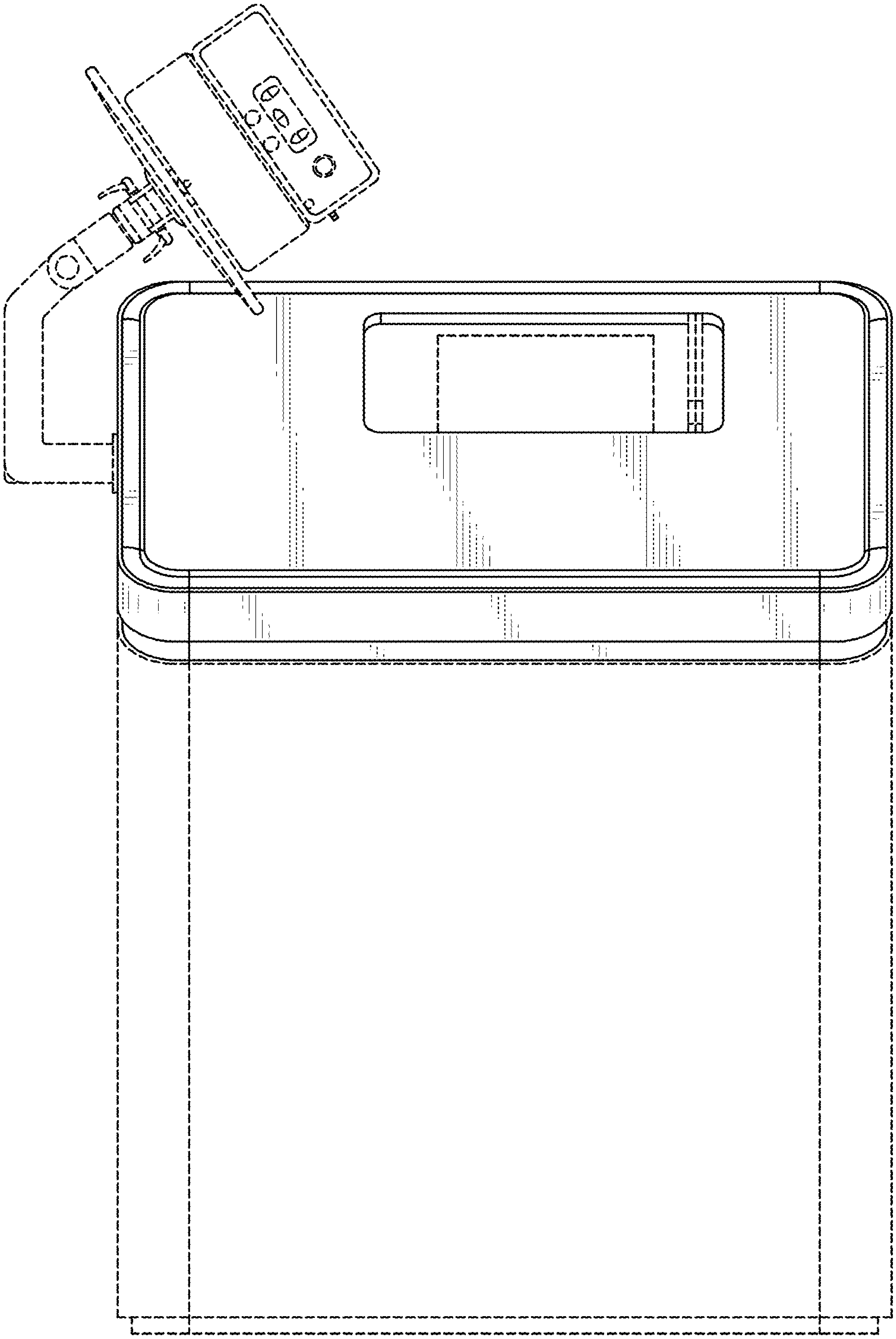


FIG. 4

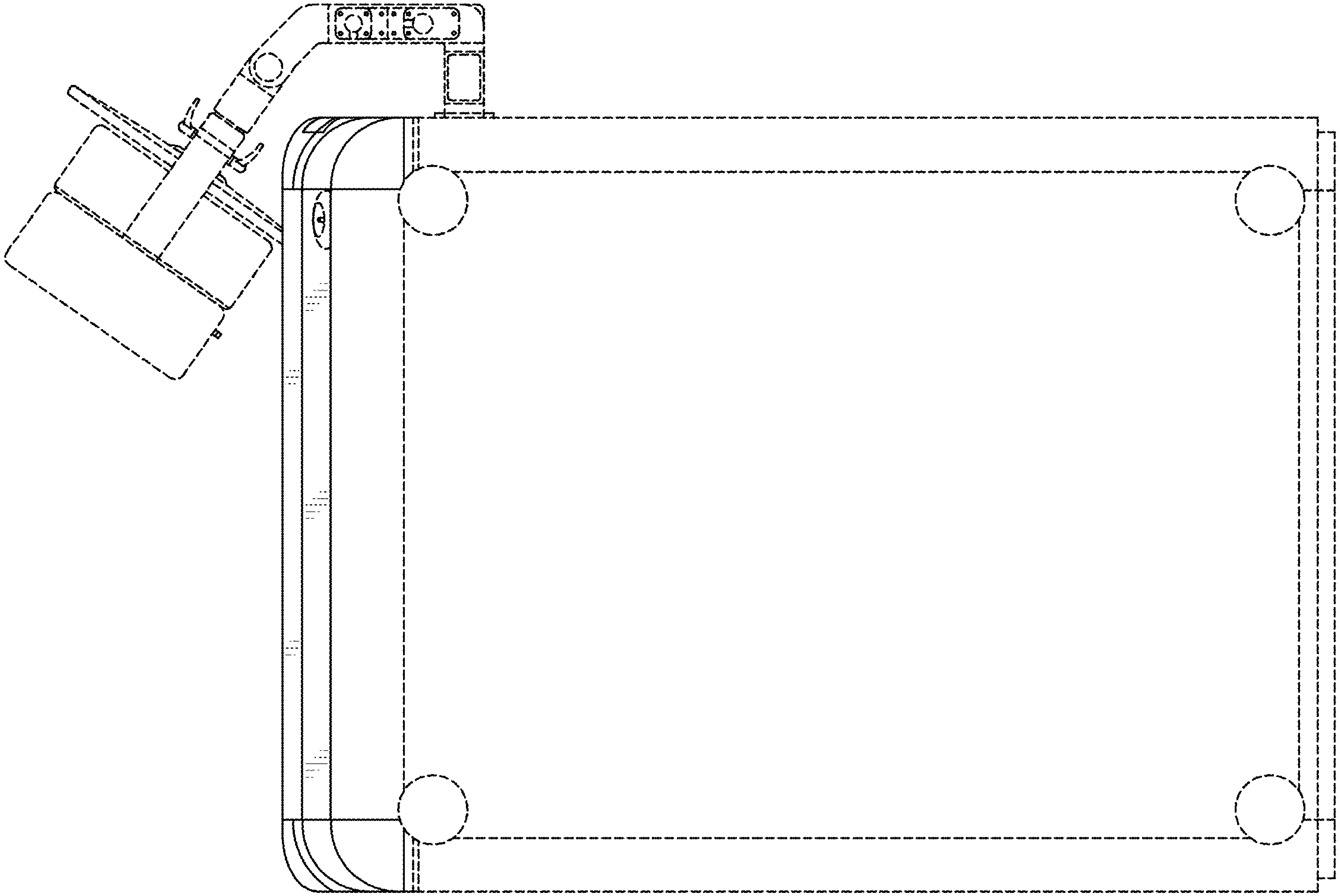


FIG. 5

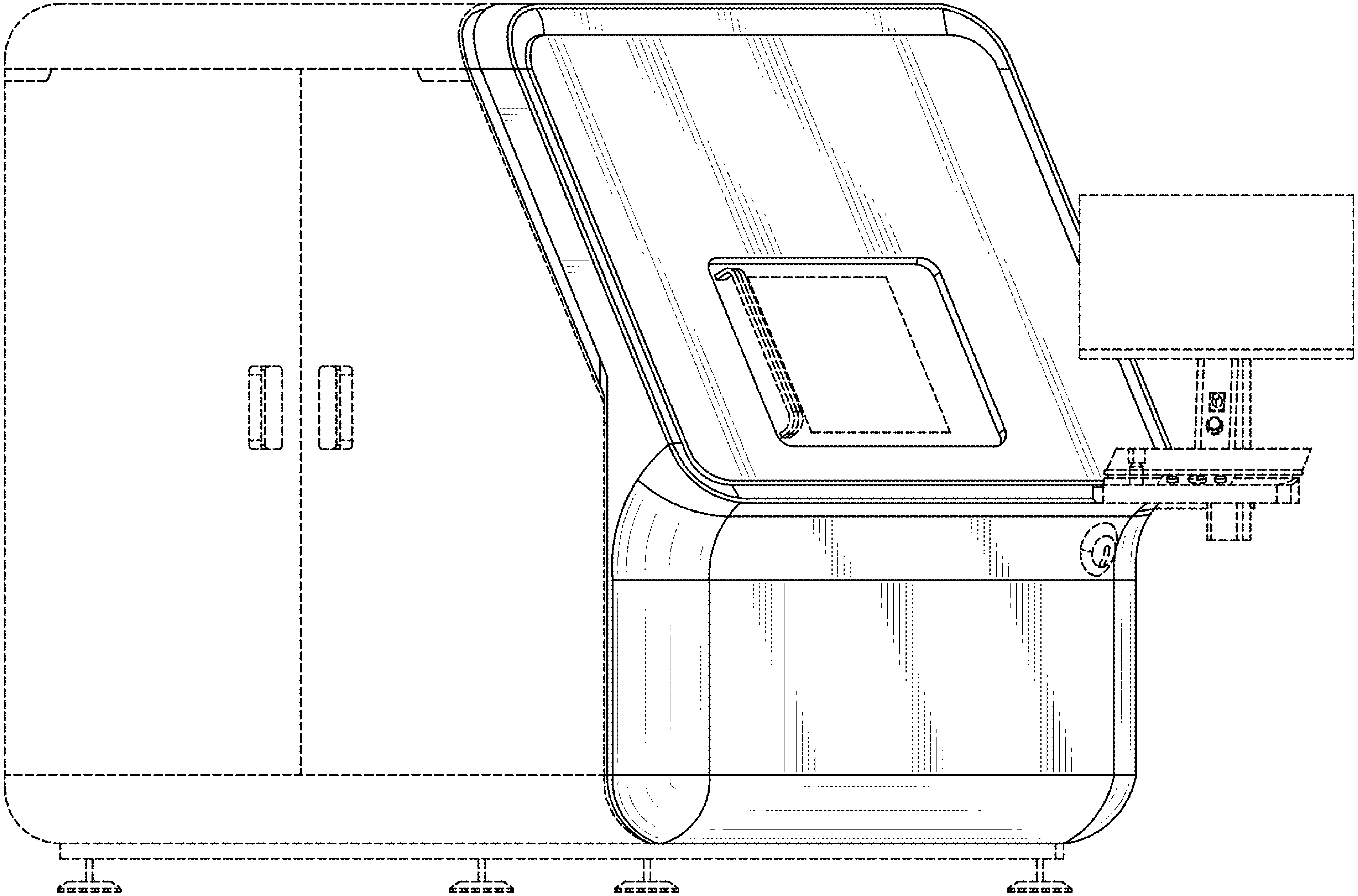


FIG. 6

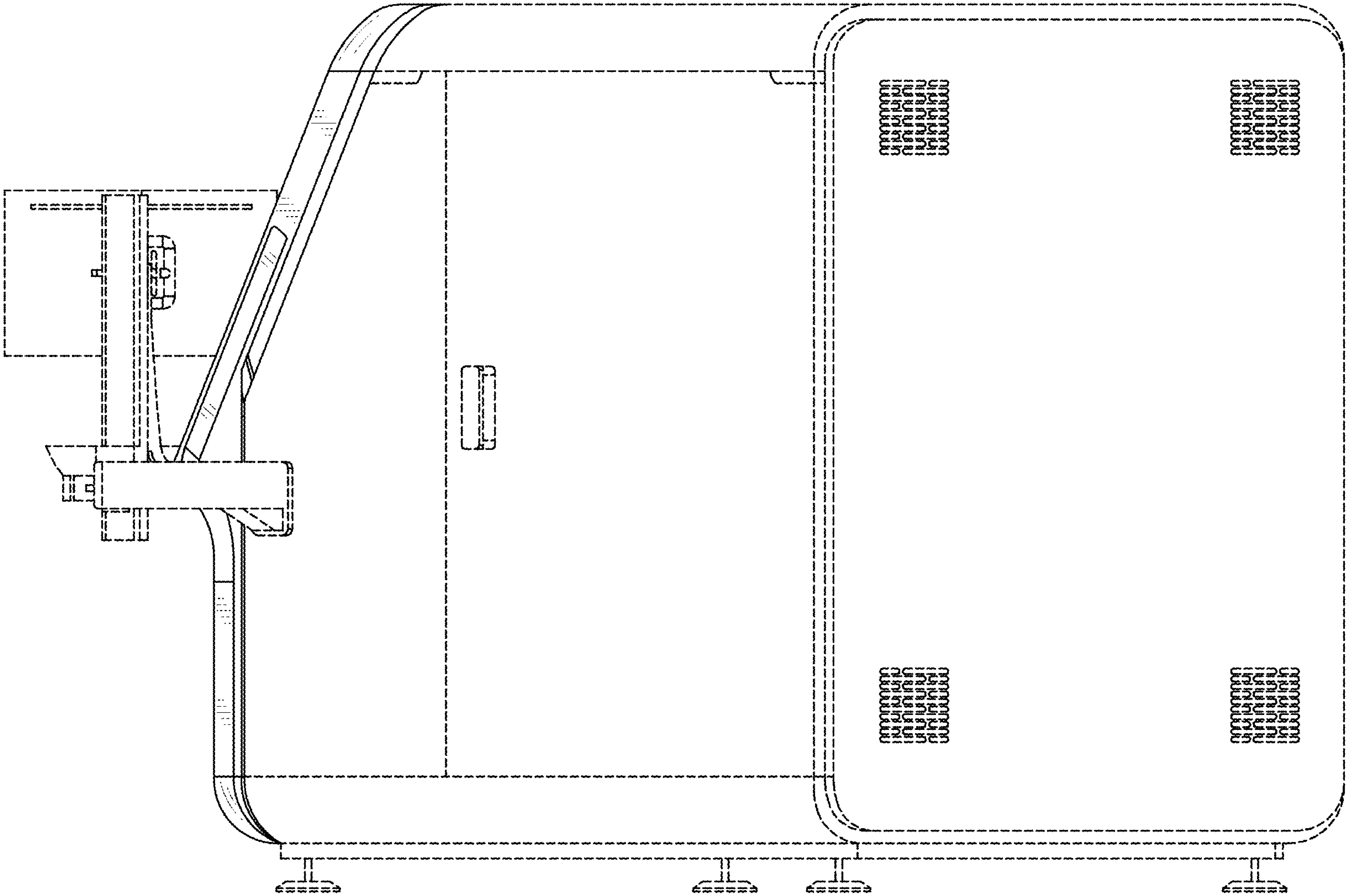


FIG. 7

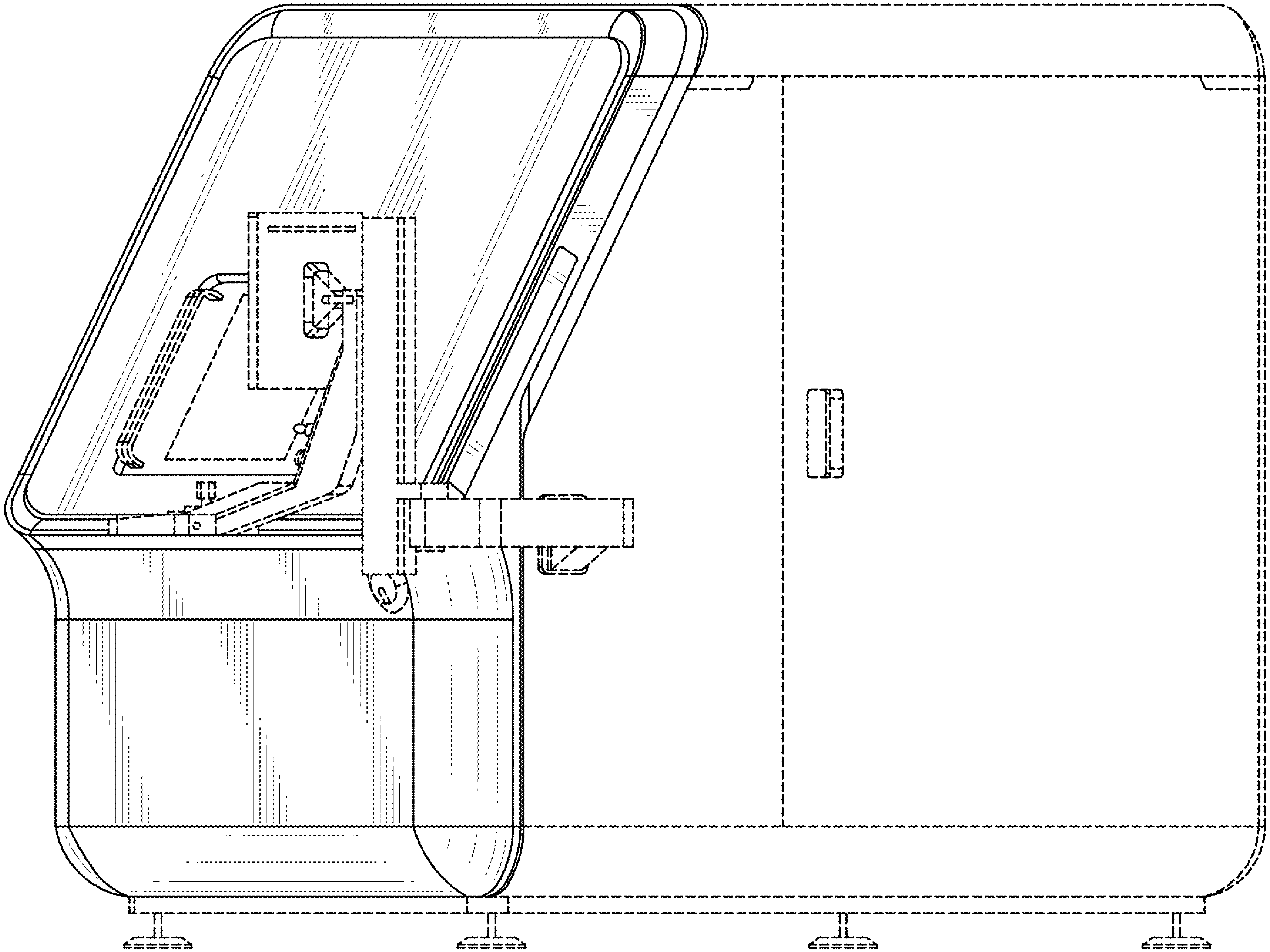


FIG. 8